

Notice of References Cited	Application/Control No. 10/715,899	Applicant(s)/Patent Under Reexamination DEERING, MICHAEL F.	
	Examiner Phu K. Nguyen	Art Unit 2628	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,313,880	11-2001	Smyers et al.	348/552
*	B	US-5,651,104	07-1997	Cosman, Michael A.	345/428
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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	U	DOBKIN et al., Computing the Discrepancy with Applications to Supersampling Patterns, ACM Transactions on Graphics, vol. 15, no. 4, 10/1996, pp. 354-376.
	V	ADAMSON et al., Adaptive Sampling of Intersective Models Exploiting Image and Object-space Coherence, ACM Transaction on graphics, 10/2005, pp. 171-227.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.